2SA1890

Silicon PNP epitaxial planar type

For low-frequency output amplification Complementary to 2SC5026

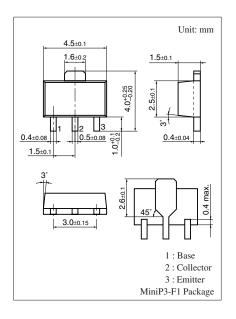
■ Features

- Low collector-emitter saturation voltage V_{CE(sat)}
- \bullet High collector-emitter voltage (Base open) V_{CEO}
- Mini power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing.

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V _{CBO}	-80	V
Collector-emitter voltage (Base open)	V _{CEO}	-80	V
Emitter-base voltage (Collector open)	V_{EBO}	-5	V
Collector current	I_{C}	-1	A
Peak collector current	I_{CP}	-1.5	A
Collector power dissipation *	P_{C}	1	W
Junction temperature	T_j	150	°C
Storage temperature	T _{stg}	-55 to +150	°C

Note) *: Printed circuit board: Copper foil area of 1 $\rm cm^2$ or more, and the board thickness of 1.7 mm for the collector portion



■ Electrical Characteristics $T_a = 25$ °C ± 3 °C

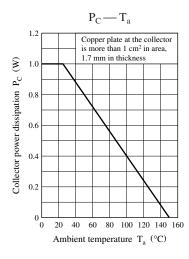
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V _{CBO}	$I_C = -10 \ \mu A, I_E = 0$	-80			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = -1 \text{ mA}, I_B = 0$	-80			V
Emitter-base voltage (Collector open)	V_{EBO}	$I_E = -10 \ \mu A, I_C = 0$	-5			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = -40 \text{ V}, I_{E} = 0$			- 0.1	μΑ
Forward current transfer ratio	h _{FE1} *2	$V_{CE} = -2 \text{ V}, I_{C} = -100 \text{ mA}$	120		340	_
	h _{FE2} *1	$V_{CE} = -2 \text{ V}, I_{C} = -500 \text{ mA}$	60			
Collector-emitter saturation voltage	V _{CE(sat)}	$I_C = -500 \text{ mA}, I_B = -50 \text{ mA}$		- 0.2	- 0.3	V
Base-emitter saturation voltage *1	V _{BE(sat)}	$I_C = -500 \text{ mA}, I_B = -50 \text{ mA}$		- 0.85	-1.2	V
Transition frequency	f_T	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		120		MHz
Collector output capacitance	C _{ob}	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		15	30	pF
(Common base, input open circuited)						

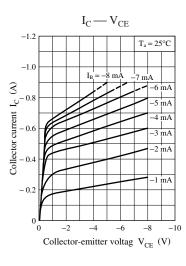
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

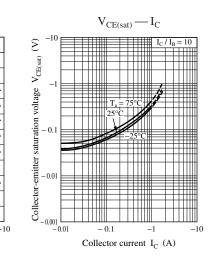
2. *1: Pulse measurement

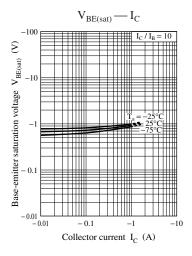
*2: Rank classification

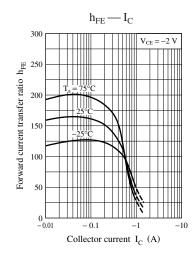
Rank	R	S
h _{FE1}	120 to 240	170 to 340

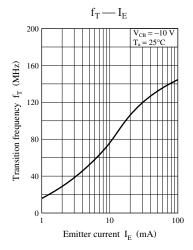


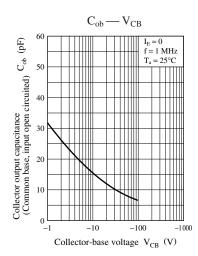












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